## SWITCHMODE ${ }^{\text {™ }}$ Series NPN Silicon Power Darlington Transistor with Base-Emitter Speedup Diode

The MJ10023 Darlington transistor is designed for high-voltage, high-speed, power switching in inductive circuits where fall time is critical. It is particularly suited for line-operated switchmode applications such as:

- AC and DC Motor Controls
- Switching Regulators
- Inverters
- Solenoid and Relay Drivers
- Fast Turn-Off Times

150 ns Inductive Fall Time @ $25^{\circ} \mathrm{C}$ (Typ) 300 ns Inductive Storage Time @ $25^{\circ} \mathrm{C}$ (Typ)

- Operating Temperature Range -65 to $+200^{\circ} \mathrm{C}$
- $100^{\circ} \mathrm{C}$ Performance Specified for:

Reversed Biased SOA with Inductive Loads
Switching Times with Inductive Loads
Saturation Voltages


Leakage Currents

## MJ10023

40 AMPERE NPN SILICON POWER DARLINGTON TRANSISTOR 400 VOLTS 250 WATTS


CASE 197A-05 TO-204AE (TO-3)

MAXIMUM RATINGS

| Rating | Symbol | Max | Unit |
| :---: | :---: | :---: | :---: |
| Collector-Emitter Voltage | $\mathrm{V}_{\text {CEO }}$ | 400 | Vdc |
| Collector-Emitter Voltage | $\mathrm{V}_{\text {CEV }}$ | 600 | Vdc |
| Emitter Base Voltage | $\mathrm{V}_{\text {EB }}$ | 80 | Vdc |
| $\begin{aligned} \hline \text { Collector Current } & \text { - Continuous } \\ & \text { Peak (1) } \end{aligned}$ | $\begin{gathered} \mathrm{I}_{\mathrm{C}} \\ \mathrm{I}_{\mathrm{CM}} \end{gathered}$ | $\begin{aligned} & 40 \\ & 80 \end{aligned}$ | Adc |
| $\begin{aligned} & \hline \text { Base Current - Continuous } \\ & \text { - Peak (1) } \end{aligned}$ | $\begin{aligned} & \hline \mathrm{I}_{\mathrm{B}} \\ & \mathrm{I}_{\mathrm{BM}} \end{aligned}$ | $\begin{aligned} & \hline 20 \\ & 40 \end{aligned}$ | Adc |
| Total Power Dissipation $@ \mathrm{~T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ $@ \mathrm{~T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ <br> Derate above $25^{\circ} \mathrm{C}$ | $P_{\text {D }}$ | $\begin{aligned} & 250 \\ & 143 \\ & 1.43 \end{aligned}$ | Watts <br> W/ ${ }^{\circ} \mathrm{C}$ |
| Operating and Storage Junction Temperature Range | $\mathrm{T}_{\mathrm{J}}, \mathrm{T}_{\text {stg }}$ | -65 to +200 | ${ }^{\circ} \mathrm{C}$ |

## THERMAL CHARACTERISTICS

| Characteristic | Symbol | Max | Unit |
| :--- | :---: | :---: | :---: |
| Thermal Resistance, Junction to Case | $\mathrm{R}_{\text {өJC }}$ | 0.7 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Maximum Lead Temperature for Soldering <br> Purposes: $1 / 8^{\prime \prime}$ from Case for 5 Seconds | $\mathrm{T}_{\mathrm{L}}$ | 275 | ${ }^{\circ} \mathrm{C}$ |

(1) Pulse Test: Pulse Width $=5 \mathrm{~ms}$, Duty Cycle $\leq 10 \%$.

ELECTRICAL CHARACTERISTICS $\left(\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}\right.$ unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| OFF CHARACTERISTICS |  |  |  |  |  |
| Collector-Emitter Sustaining Voltage (Table 1) $\left(I_{C}=100 \mathrm{~mA}, \mathrm{I}_{\mathrm{B}}=0\right)$ | $\mathrm{V}_{\text {CEO(sus) }}$ | 400 | - | - | Vdc |
| Collector Cutoff Current $\begin{aligned} & \left(\mathrm{V}_{\mathrm{CEV}}=\text { Rated Value, } \mathrm{V}_{\mathrm{BE} \text { (off) }}=1.5 \mathrm{Vdc}\right) \\ & \left(\mathrm{V}_{\mathrm{CEV}}=\text { Rated Value, } \mathrm{V}_{\mathrm{BE}(\text { off })}=1.5 \mathrm{Vdc}, \mathrm{~T}_{\mathrm{C}}=150^{\circ} \mathrm{C}\right) \end{aligned}$ | ICEV |  | - | $\begin{gathered} 0.25 \\ 5.0 \end{gathered}$ | mAdc |
| Collector Cutoff Current $\left(\mathrm{V}_{\mathrm{CE}}=\text { Rated } \mathrm{V}_{\mathrm{CEV}}, \mathrm{R}_{\mathrm{BE}}=50 \Omega, \mathrm{~T}_{\mathrm{C}}=100^{\circ} \mathrm{C}\right)$ | ICER | - | - | 5.0 | mAdc |
| Emitter Cutoff Current $\left(\mathrm{V}_{\mathrm{EB}}=2.0 \mathrm{~V}, \mathrm{I}_{\mathrm{C}}=\mathrm{O}\right)$ | IEbo | - | - | 175 | mAdc |

## SECOND BREAKDOWN

| Second Breakdown Collector Current with Base Forward Biased | $\mathrm{I}_{\mathrm{S} / \mathrm{b}}$ |  | See Figure 13 |  |
| :--- | :---: | :---: | :---: | :---: |
| Clamped Inductive SOA with Base Reverse Biased | RBSOA |  | See Figure 14 |  |

ON CHARACTERISTICS (1)

| DC Current Gain $\left(\mathrm{I}_{\mathrm{C}}=10 \mathrm{Adc}, \mathrm{~V}_{\mathrm{CE}}=5.0 \mathrm{~V}\right)$ | $\mathrm{h}_{\text {FE }}$ | 50 | - | 600 | - |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\begin{aligned} & \text { Collector-Emitter Saturation Voltage } \\ & \text { ( } \left.I_{C}=20 \mathrm{Adc}, I_{B}=1.0 \mathrm{Adc}\right) \\ & \left(I_{C}=40 \mathrm{Adc}, I_{B}=5.0 \mathrm{Adc}\right) \\ & \left(I_{C}=20 \mathrm{Adc}, I_{B}=10 \mathrm{Adc}, \mathrm{~T}_{\mathrm{C}}=100^{\circ} \mathrm{C}\right) \end{aligned}$ | $\mathrm{V}_{\text {CE(sat) }}$ | $-$ | - | $\begin{aligned} & 2.2 \\ & 5.0 \\ & 2.5 \end{aligned}$ | Vdc |
| $\begin{aligned} & \text { Base-Emitter Saturation Voltage } \\ & \quad\left(I_{C}=20 \mathrm{Adc}, \mathrm{I}_{\mathrm{B}}=1.2 \mathrm{Adc}\right) \\ & \left(I_{C}=20 \mathrm{Adc}, I_{\mathrm{B}}=1.2 \mathrm{Adc}, \mathrm{~T}_{\mathrm{C}}=100^{\circ} \mathrm{C}\right) \end{aligned}$ | $\mathrm{V}_{\mathrm{BE} \text { (sat) }}$ |  |  | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ | Vdc |
| Diode Forward Voltage $\text { ( } \left.\mathrm{IF}_{\mathrm{F}}=20 \mathrm{Adc}\right)$ | $V_{f}$ | - | 2.5 | 5.0 | Vdc |

## DYNAMIC CHARACTERISTICS

| Output Capacitance <br> $\left(\mathrm{V}_{\mathrm{CB}}=10 \mathrm{Vdc}, \mathrm{I}_{\mathrm{E}}=0, \mathrm{f}_{\text {test }}=1.0 \mathrm{kHz}\right)$ | $\mathrm{C}_{\mathrm{ob}}$ | 150 | - | 600 | pF |
| :---: | :---: | :---: | :---: | :---: | :---: |

## SWITCHING CHARACTERISTICS

| Resistive Load (Table 1) |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Delay Time | $\begin{gathered} \left(\mathrm{V}_{\mathrm{CC}}=250 \mathrm{Vdc}, \mathrm{I}_{\mathrm{C}}=20 \mathrm{~A}, \mathrm{I}_{\mathrm{B} 1}=1.0 \mathrm{Adc},\right. \\ \mathrm{V}_{\mathrm{BE}(\text { off })}=5.0 \mathrm{~V}, \mathrm{t}_{\mathrm{p}}=50 \mu \mathrm{~s}, \\ \text { Duty Cycle } \leq 2.0 \%) \end{gathered}$ | $t_{d}$ | - | 0.03 | 0.2 | $\mu \mathrm{s}$ |
| Rise Time |  | $\mathrm{tr}_{r}$ | - | 0.4 | 1.2 | $\mu \mathrm{s}$ |
| Storage Time |  | $\mathrm{t}_{\text {s }}$ | - | 0.9 | 2.5 | $\mu \mathrm{s}$ |
| Fall Time |  | $t_{f}$ | - | 0.3 | 0.9 | $\mu \mathrm{s}$ |
| Inductive Load, Clamped (Table 1) |  |  |  |  |  |  |
| Storage Time | $\begin{gathered} \left(\mathrm{I}_{\mathrm{CM}}=20 \mathrm{~A}, \mathrm{~V}_{\mathrm{CEM}}=250 \mathrm{~V}, \mathrm{I}_{\mathrm{B} 1}=1.0 \mathrm{~A},\right. \\ \left.\mathrm{V}_{\mathrm{BE}(\text { off })}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{C}}=100^{\circ} \mathrm{C}\right) \end{gathered}$ | $\mathrm{t}_{\mathrm{sv}}$ | - | 1.9 | 4.4 | $\mu \mathrm{s}$ |
| Crossover Time |  | $\mathrm{t}_{\mathrm{c}}$ | - | 0.6 | 2.0 | $\mu \mathrm{s}$ |
| Fall Time |  | $\mathrm{t}_{\mathrm{fi}}$ | - | 0.3 | - | $\mu \mathrm{s}$ |
| Storage Time | $\begin{gathered} \left(\mathrm{I}_{\mathrm{CM}}=20 \mathrm{~A}, \mathrm{~V}_{\mathrm{CEM}}=250 \mathrm{~V}, \mathrm{I}_{\mathrm{B} 1}=1.0 \mathrm{~A},\right. \\ \left.\mathrm{V}_{\mathrm{BE} \text { (off) })}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{C}}=25^{\circ} \mathrm{C}\right) \end{gathered}$ | $\mathrm{t}_{\mathrm{sv}}$ | - | 1.0 | - | $\mu \mathrm{s}$ |
| Crossover Time |  | $\mathrm{t}_{\mathrm{c}}$ | - | 0.3 | - | $\mu \mathrm{s}$ |
| Fall Time |  | $\mathrm{t}_{\mathrm{fi}}$ | - | 0.15 | - | $\mu \mathrm{s}$ |

[^0]

Figure 1. DC Current Gain


Figure 3. Collector-Emitter Saturation Voltage


Figure 5. Collector Cutoff Region


Figure 2. Collector Saturation Region


Figure 4. Base-Emitter Saturation Voltage


Figure 6. $\mathrm{C}_{\mathrm{ob}}$, Output Capacitance

## MJ10023

Table 1. Test Conditions for Dynamic Performance

|  | $\mathrm{V}_{\text {CEO(sus) }}$ | RBSOA AND INDUCTIVE SWITCHING | RESISTIVE SWITCHING |
| :---: | :---: | :---: | :---: |
|  | PW Varied to Attain $\mathrm{I}_{\mathrm{C}}=100 \mathrm{~mA}$ | INDUCTIVE TEST CIRCUIT | TURN-ON TIME <br> $I_{B 1}$ adjusted to obtain the forced $h_{\text {FE }}$ desired <br> TURN-OFF TIME <br> Use inductive switching driver as the input to the resistive test circuit. |
|  | $\begin{aligned} & \mathrm{L}_{\text {coil }}=10 \mathrm{mH}, \mathrm{~V}_{\mathrm{CC}}=10 \mathrm{~V} \\ & \mathrm{R}_{\text {coil }}=0.7 \Omega \\ & \mathrm{~V}_{\text {clamp }}=\mathrm{V}_{\mathrm{CEO} \text { (sus) }} \end{aligned}$ | $\begin{aligned} & \mathrm{L}_{\text {coil }}=180 \mu \mathrm{H} \\ & \mathrm{R}_{\text {coil }}=0.05 \Omega \\ & \mathrm{~V}_{\mathrm{CC}}=20 \mathrm{~V} \end{aligned}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=250 \mathrm{~V} \\ & \mathrm{R}_{\mathrm{L}}=12.5 \Omega \\ & \text { Pulse Width }=25 \mu \mathrm{~s} \end{aligned}$ |
|  |  |  | RESISTIVE TEST CIRCUIT |

## MJ10023



Figure 7. Inductive Switching Measurements


Figure 8. Typical Peak Reverse Base Current


Figure 9. Typical Inductive Switching Times

## MJ10023

## SWITCHING TIMES NOTE

In resistive switching circuits, rise, fall, and storage times have been defined and apply to both current and voltage waveforms since they are in phase. However, for inductive loads which are common to SWITCHMODE power supplies and hammer drivers, current and voltage waveforms are not in phase. Therefore, separate measurements must be made on each waveform to determine the total switching time. For this reason, the following new terms have been defined.
$\mathrm{t}_{\mathrm{sv}}=$ Voltage Storage Time, $90 \% \mathrm{I}_{\mathrm{B} 1}$ to $10 \% \mathrm{~V}_{\text {CEM }}$
$\mathrm{t}_{\mathrm{rv}}=$ Voltage Rise Time, $10-90 \% \mathrm{~V}_{\mathrm{CEM}}$
$\mathrm{t}_{\mathrm{fi}}=$ Current Fall Time, $90-10 \% \mathrm{I}_{\mathrm{CM}}$
$\mathrm{t}_{\mathrm{ti}}=$ Current Tail, $10-2 \% \mathrm{I}_{\mathrm{CM}}$
$\mathrm{t}_{\mathrm{c}}=$ Crossover Time, $10 \% \mathrm{~V}_{\mathrm{CEM}}$ to $10 \% \mathrm{I}_{\mathrm{CM}}$
An enlarged portion of the inductive switching waveform is shown in Figure 7 to aid on the visual identity of these terms.

For the designer, there is minimal switching loss during storage time and the predominant switching power losses occur during the crossover interval and can be obtained using the standard equation from $\mathrm{AN}-222 \mathrm{~A}$ :

$$
P_{S W T}=1 / 2 V_{C C} I_{C}\left(t_{C}\right) f
$$

In general, $\mathrm{t}_{\mathrm{rv}}+\mathrm{t}_{\mathrm{fi}} \cong \mathrm{t}_{\mathrm{c}}$. However, at lower test currents this relationship may not be valid.

As is common with most switching transistors, resistive switching is specified at $25^{\circ} \mathrm{C}$ and has become a benchmark for designers. However, for designers of high frequency converter circuits, the user orientated specifications which make this a "SWITCHMODE" transistor are the inductive switching speeds ( $\mathrm{t}_{\mathrm{c}}$ and $\mathrm{t}_{\mathrm{sv}}$ ) which are guaranteed at $100^{\circ} \mathrm{C}$.

RESISTIVE SWITCHING


Figure 10. Typical Turn-On Switching Times


Figure 11. Typical Turn-Off Switching Times


Figure 12. Thermal Response

The Safe Operating Area figures shown in Figures 13 and 14 are specified for these devices under the test conditions shown.


Figure 13. Maximum Forward Bias Safe Operating Area


SAFE OPERATING AREA INFORMATION

## FORWARD BIAS

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate $I_{C}-V_{C E}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 13 is based on $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C} ; \mathrm{T}_{\mathrm{J}(\mathrm{pk})}$ is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to $10 \%$ but must be derated when $\mathrm{T}_{\mathrm{C}} \geq 25^{\circ} \mathrm{C}$. Second breakdown limitations do not derate the same as thermal limitations. Allowable current at the voltages shown on Figure 13 may be found at any case temperature by using the appropriate curve on Figure 15.
$\mathrm{T}_{\mathrm{J}(\mathrm{pk})}$ may be calculated from the data in Figure 12. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

## REVERSE BIAS

For inductive loads, high voltage and high current must be sustained simultaneously during turn-off, in most cases, with the base to emitter junction reverse biased. Under these conditions the collector voltage must be held to a safe level at or below a specific value of collector current. This can be accomplished by several means such as active clamping, RC snubbing, load line shaping, etc. The safe level for these devices is specified as Reverse Bias Safe Operating Area and represents the voltage-current condition allowable during reverse biased turn-off. This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode. Figure 14 gives the RBSOA characteristics.

Figure 14. Maximum RBSOA, Reverse Bias Safe Operating Area


Figure 15. Power Derating

## PACKAGE DIMENSIONS

CASE 197A-05
TO-204AE (TO-3)
TO-204AE (TO-3)
ISSUE J


| NOTES: <br> 1. DIMEN Y14.5N <br> 2. CONTR |  |  | ERANC <br> N: INC | G PER |
| :---: | :---: | :---: | :---: | :---: |
|  |  | HES | MILLIM | TERS |
| DIM | MIN | MAX | MIN | MAX |
| A | 1.530 | REF | 38.86 | REF |
| B | 0.990 | 1.050 | 25.15 | 26.67 |
| C | 0.250 | 0.335 | 6.35 | 8.51 |
| D | 0.057 | 0.063 | 1.45 | 1.60 |
| E | 0.060 | 0.070 | 1.53 | 1.77 |
| G | 0.430 BSC |  | 10.92 BSC |  |
| H | 0.215 BSC |  | 5.46 BSC |  |
| K | 0.440 | 0.480 | 11.18 | 12.19 |
| L | 0.665 BSC |  | 16.89 BSC |  |
| N | 0.760 | 0.830 | 19.31 | 21.08 |
| Q | 0.151 | 0.165 | 3.84 | 4.19 |
| U | 1.187 BSC |  | 30.15 BSC |  |
| V | 0.131 | 0.188 | 3.33 | 4.77 |
| STYLE 1: |  |  |  |  |
| PIN 1. BASE |  |  |  |  |
| 2. EMITTER |  |  |  |  |
| CASE: COLLECTOR |  |  |  |  |

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#### Abstract

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[^0]:    (1) Pulse Test: PW $=300 \mu \mathrm{~s}$, Duty Cycle $\leq 2 \%$.

